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**Information technology — Radio  
frequency identification device  
conformance test methods —**

**Part 6:  
Test methods for air interface  
communications at 860 MHz to 960 MHz**

iTeh STANDARD PREVIEW

*Technologies de l'information — Méthodes d'essai de conformité du  
dispositif d'identification de radiofréquence —*

*Partie 6: Méthodes d'essai pour des communications d'une interface  
d'air à 860 MHz et jusqu'à 960 MHz*

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Published in Switzerland

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## Foreword

ISO (the International Organization for Standardization) and IEC (the International Electrotechnical Commission) form the specialized system for worldwide standardization. National bodies that are members of ISO or IEC participate in the development of International Standards through technical committees established by the respective organization to deal with particular fields of technical activity. ISO and IEC technical committees collaborate in fields of mutual interest. Other international organizations, governmental and non-governmental, in liaison with ISO and IEC, also take part in the work. In the field of information technology, ISO and IEC have established a joint technical committee, ISO/IEC JTC 1.

International Standards are drafted in accordance with the rules given in the ISO/IEC Directives, Part 2.

The main task of the joint technical committee is to prepare International Standards. Draft International Standards adopted by the joint technical committee are circulated to national bodies for voting. Publication as an International Standard requires approval by at least 75 % of the national bodies casting a vote.

In exceptional circumstances, when the joint technical committee has collected data of a different kind from that which is normally published as an International Standard ("state of the art", for example), it may decide to publish a Technical Report. A Technical Report is entirely informative in nature and shall be subject to review every five years in the same manner as an International Standard.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO and IEC shall not be held responsible for identifying any or all such patent rights.

ISO/IEC TR 18047-6 was prepared by Joint Technical Committee ISO/IEC JTC 1, *Information technology*, Subcommittee SC 31, *Automatic identification and data capture techniques*.

This third edition cancels and replaces the second edition (ISO/IEC TR 18047-6:2008), which has been technically revised.

ISO/IEC TR 18047 consists of the following parts, under the general title *Information technology — Radio frequency identification device conformance test methods*:

- *Part 2: Test methods for air interface communications below 135 kHz*
- *Part 3: Test methods for air interface communications at 13,56 MHz*
- *Part 4: Test methods for air interface communications at 2,45 GHz*
- *Part 6: Test methods for air interface communications at 860 MHz to 960 MHz*
- *Part 7: Test methods for active air interface communications at 433 MHz*

## Introduction

ISO/IEC 18000 defines the air interfaces for radio frequency identification (RFID) devices used in item management applications. ISO/IEC 18000-6 defines the air interface for these devices operating at frequencies from 860 MHz to 960 MHz.

ISO/IEC TR 18047 provides test methods for conformance with the various parts of ISO/IEC 18000.

Each part of ISO/IEC TR 18047 contains all measurements required to be made on a product in order to establish whether it conforms to the corresponding part of ISO/IEC 18000. For this part of ISO/IEC TR 18047, each interrogator and each tag needs to support at least one of the types A or B or C or D.

NOTE Measurement of tag and interrogator performance is covered by the multiple parts of ISO/IEC 18046.

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# Information technology — Radio frequency identification device conformance test methods —

## Part 6:

## Test methods for air interface communications at 860 MHz to 960 MHz

### 1 Scope

This part of ISO/IEC TR 18047 defines test methods for determining the conformance of radio frequency identification (RFID) devices (tags and interrogators) for item management with the specifications given in ISO/IEC 18000-6, but does not apply to the testing of conformity with regulatory or similar requirements.

The test methods require only that the mandatory functions, and any optional functions which are implemented, be verified. This can, in appropriate circumstances, be supplemented by further, application-specific functionality criteria that are not available in the general case.

The interrogator and tag conformance parameters in this part of ISO/IEC TR 18047 are the following:

- type-specific conformance parameters including nominal values and tolerances;
- parameters that apply directly affecting system functionality and inter-operability.

The following are not included in this part of ISO/IEC TR 18047:

- parameters that are already included in regulatory test requirements;
- high-level data encoding conformance test parameters (these are specified in ISO/IEC 15962).

Unless otherwise specified, the tests in this part of ISO/IEC TR 18047 are to be applied exclusively to RFID tags and interrogators defined in ISO/IEC 18000-6.

Clause 5 describes all necessary conformance tests for ISO/IEC 18000-6 Type A.

Clause 6 describes all necessary conformance tests for ISO/IEC 18000-6 Type B.

Clause 7 describes all necessary conformance tests for ISO/IEC 18000-6 Type C.

Clause 8 describes all necessary conformance tests for ISO/IEC 18000-6 Type D.

Clause 9 describes all necessary conformance tests for ISO/IEC 18000-6 Type C Battery Assisted Passive (BAP), whereas optional features will only be tested when supported.

Clause 10 describes all necessary conformance tests for ISO/IEC 18000-6 Type C Sensor support, whereas optional features will only be tested when supported.

## 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendment s) applies.

ISO/IEC 18000-6, *Information technology — Radio frequency identification for item management — Part 6: Parameters for air interface communications at 860 MHz to 960 MHz*

ISO/IEC 19762 (all parts), *Information technology — Automatic identification and data capture (AIDC) techniques — Harmonized vocabulary*

## 3 Terms, definitions, symbols and abbreviated terms

### 3.1 Terms and definitions

For the purposes of this document, the terms and definitions given in ISO/IEC 19762 apply.

### 3.2 Symbols

For the purposes of this document, the symbols given in ISO/IEC 19762 and the following apply.

D	Modulation depth of data coding pulse
d1	Distance between the interrogator and test antenna
d2	Distance between test antenna and DUT tag
ds	Distance between the interrogator antenna and sense antenna
dT,IA	Interrogator antenna to tag distance
dT,MA	Measurement antenna to tag distance
dTE	Distance between the interrogator antenna and tag emulator
GI	Interrogator antenna gain
GIA	Gain of interrogator antenna
GMA	Gain of measurement antenna
K	Calibration factor
L	Maximum interrogator antenna dimension
M	Modulation index
PI	Delivered power at the carrier frequency
PM	Measured power at the carrier frequency
Tf	Fall time
Tr	Rise time

### 3.3 Abbreviated terms

For the purposes of this document, the abbreviated terms given in ISO/IEC 19762 and the following apply.

DUT	Device under test
RCS	Radar cross-section
$\Delta$ RCS	Change in radar cross-section
RBW	Resolution bandwidth
VBW	Video bandwidth

### 3.4 Default conditions applicable to the test methods

#### 3.4.1 Test environment

Unless otherwise specified, testing shall take place in an environment of temperature  $23\text{ }^{\circ}\text{C} \pm 3\text{ }^{\circ}\text{C}$  and of non-condensing humidity from 40 % to 60 %.

#### 3.4.2 Pre-conditioning

Where pre-conditioning is required by the test method, the interrogators and tags to be tested shall be conditioned to the test environment for an appropriate time period, which shall be recorded.

#### 3.4.3 Default tolerance

Unless otherwise specified, a default tolerance of  $\pm 5\%$  shall be applied to the quantity values given to specify the characteristics of the test equipment (e.g. linear dimensions) and the test method procedures (e.g. test equipment adjustments).  
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#### 3.4.4 Noise floor at test location

Noise floor at test location shall be measured with the spectrum analyser using the same conditions as for the measurement of the DUT.

The spectrum analyser shall measure the noise for at least 1 minute.

The maximum of the measured amplitude shall be 20 dB below the value of the amplitude of the measured tag backscatter operating at minimum power ( $P_{l,min}$ , see clause 5.2.2.2), and the tag placed at  $10\lambda$  from the measurement antenna.

Special attention has to be given to spurious emissions, e.g., insufficiently shielded computer monitors. The electromagnetic test conditions of the measurements shall be checked by performing the measurements with and without a tag in the field.

#### 3.4.5 Total measurement uncertainty

The total measurement uncertainty for each quantity determined by these test methods shall be stated in the test report.

NOTE Basic information is given in ISO Guide 98-3:2008.

## 4 Setup of test equipment

### 4.1 Setup of test equipment for interrogator tests

#### 4.1.1 General

The DUT shall be an interrogator including an antenna.

All conformance measurements and setups shall be done in an anechoic chamber as defined in Annex A.

Dependent of the regulatory requirements all measurements shall be done at one of the test frequencies in Table 1.

**Table 1 — Test frequencies**

Test carrier frequency	Comment
866 MHz	Recommended for tests under European regulations
910 MHz	Recommended for tests under Korean or US regulations
922 MHz	Recommended for tests under Australian regulations
953 MHz	Recommended for tests under Japan regulations

NOTE With the test frequencies specified in Table 1 all frequencies of the entire band from 860 MHz to 960 MHz are within  $\pm 2,5$  % of one of the test frequencies.

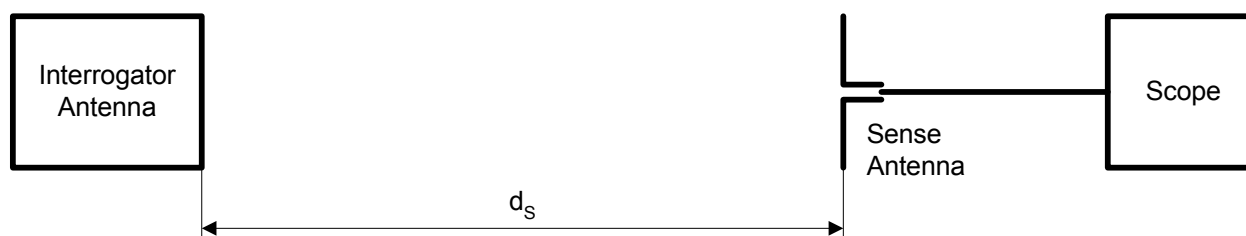
#### 4.1.2 Sense antenna

Where applicable, tests shall be carried out using a sense antenna, which shall be a substantially non-reactive non-radiating load of  $50\ \Omega$  equipped with an antenna connector. The Voltage Standing Wave Ratio (VSWR) at the  $50\ \Omega$  connector shall not be greater than 1,2 : 1 over the frequency range of the measurement.

#### 4.1.3 Test apparatus and test circuits for ISO/IEC 18000-6 Type A and B interrogator

##### 4.1.3.1 Interrogator modulation test setup

For this test the sense antenna shall always be placed and orientated for optimum field strength reception in the direction of the major power radiation of the interrogator antenna according Figure 1 at a distance  $d_s$  which is defined in clause 5.1.1.2.



**Figure 1 — Interrogator modulation test setup**

#### 4.1.3.2 Interrogator demodulation and turn around time test setup

For this test the tag emulator as defined in Annex F shall be placed and orientated for optimum field strength reception in the direction of the major power radiation of the interrogator according Figure 2 at a distance  $d_{TE}$ , which is defined in clause 5.1.2.2.

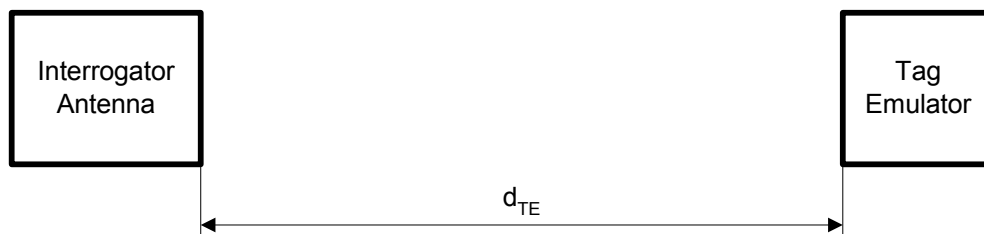


Figure 2 — Interrogator demodulation and turn around test setup

#### 4.1.4 Test apparatus and test circuits for ISO/IEC 18000-6 Type C interrogator

The DUT shall be an interrogator including an antenna.

For this test, the sense antenna shall always be placed according to Figure 3. The distance between an interrogator antenna and a sense antenna shall be  $d_1$ . The sense antenna shall be placed in the optimum orientation so as to receive the highest possible power level radiated by the interrogator antenna.



Figure 3 — Interrogator test setup

For some interrogator tests a tag emulator as defined in Annex F shall be used, the tag emulator shall be placed and orientated for optimum field strength reception in the direction of the major power radiation of the interrogator.

### 4.2 Setup of test equipment for tag tests

#### 4.2.1 General

The DUT shall be a tag including all means in order to be capable to communicate with an interrogator.

When tests require use of an interrogator this shall be an interrogator including antenna that conforms to ISO/IEC 18000-6 according to the methods defined in this Type of ISO/IEC TR 18047, or it shall be a signal generator including antenna. Furthermore, the interrogator shall support the minimum tag response to interrogator command turn around time.

The interrogator antenna shall fulfil the specification of Table 2.

Table 2 — Interrogator antenna requirements for tag tests

Symbol	Parameter	Minimum Value	Maximum Value
L	Maximum Interrogator antenna dimension	0,1 m	$\sqrt{\frac{\lambda d_{T,IA}}{2}}$
$G_I$	Interrogator antenna gain	2 dBi	8 dBi

All conformance measurements and setups shall be done in an anechoic chamber as defined in Annex A.

Dependent of the regulatory requirements all measurements shall be done at either of the test frequencies in Table 1.

#### 4.2.2 Test apparatus and test circuits for ISO/IEC 18000-6 Type A, B and D tags

##### 4.2.2.1 Tag demodulation and turn around time test setup

For this test the tag shall be placed and oriented for optimum field strength reception in the direction of the major power radiation of the interrogator in a distance

$$d_{T,IA} > \frac{2L^2}{\lambda}, d_{T,MA} > \frac{2L^2}{\lambda}$$

with L being the maximum dimension of the interrogator antenna according to Figure 4.

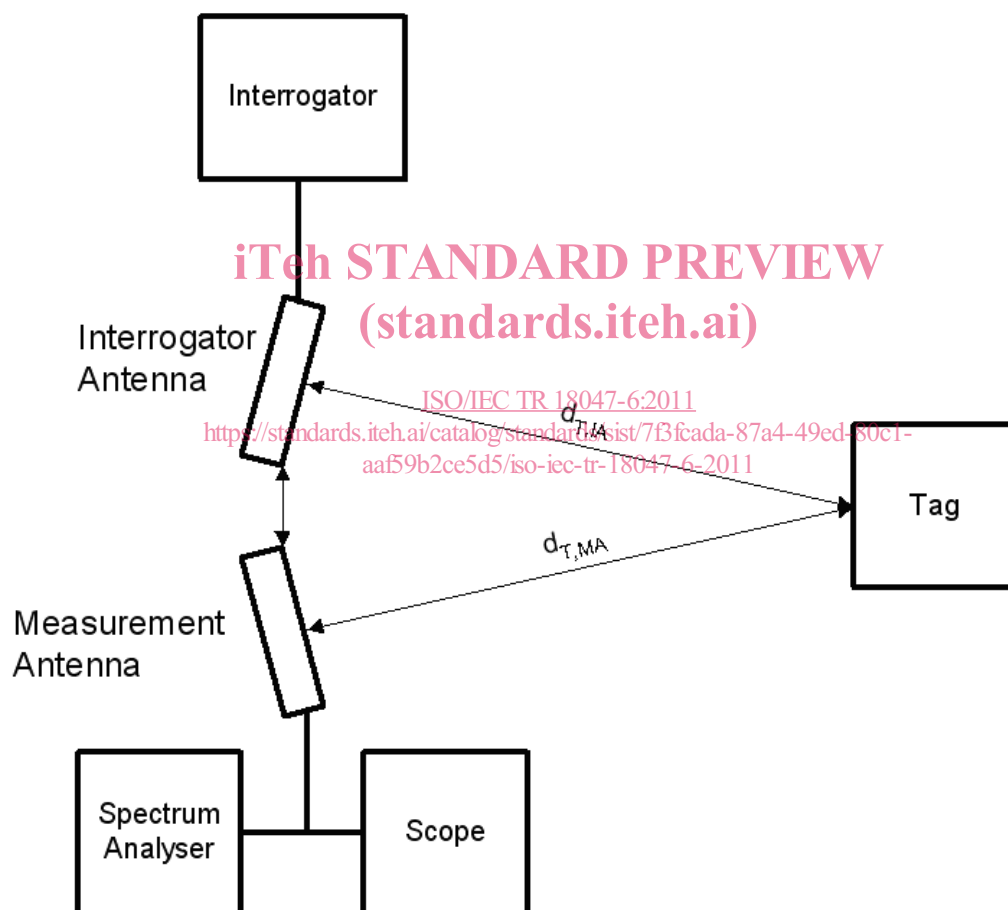


Figure 4 — Tag demodulation test setup

##### 4.2.2.2 Tag backscatter test setup

For this test the test interrogator antenna setup, where the interrogator may alternately also be realized with a vector signal generator according to Annex H, shall consist of a set of two mechanically assembled antennas specifically designed to reduce the signal coupling between each other. One shall be used as interrogator antenna while the second, shall be used as measurement antenna and shall be connected either to a spectrum analyser or to an oscilloscope as specified according to Annex D.

The main lobe axis of these two antennas cross each other with an angle value that shall be lower than 15°. The tag under test shall be placed at this focal point and oriented for optimum field strength reception.

The distances between the tag and the antennas are  $d_{T,IA}$  and  $d_{T,MA}$  respectively (see Figure 4).

The tag backscatter test setup parameters are defined in Table 3.

**Table 3 — Tag backscatter setup parameters**

Symbol	Name	Description
$d_{T,IA}$	Interrogator antenna to tag distance	
$d_{T,MA}$	Measurement antenna to tag distance	
$G_{IA}$	Gain of interrogator antenna	The maximum 3 dB beam width shall be $\pm 35^\circ$
$G_{MA}$	Gain of measurement antenna	The maximum 3 dB beam width shall be $\pm 35^\circ$

The residual signal coupling between the two antennas shall be measured in free space, and anechoic or similar RF absorbing material shall be used between two antennas to increase isolation up to 45 dB when the value in free space is not better than 45 dB.

L shall be the greater value of the maximum electrical dimension of the Interrogator and Measurement Antenna.

The spectrum analyser shall be to a RBW of 30 kHz, a VBW of 100 kHz. The minimum span should be at least 1 MHz or 8 times the data rate, whichever is greater. The frequency analyser shall use max peak detection.

For this test the tag shall be setup to provide only one modulation frequency. Therefore the tag shall except for the preamble, only reply with a bit stream of zero data bits.

#### 4.2.2.3 Tag response time

The setup for this test shall be as described in chapter 4.2.2.1.

#### 4.2.2.4 Tag bit rate accuracy test setup

The setup for this test shall be as described in chapter 4.2.2.1.

#### 4.2.2.5 Tag state storage time test setup

The setup for this test shall be as described in chapter 4.2.2.1.

### 4.2.3 Test apparatus and test circuits for ISO/IEC 18000-6 Type C tags

The DUT shall be a tag including all means in order to be capable to communicate with an interrogator.

For this test the tag shall be placed and oriented for optimum field strength reception in the direction of the major power radiation of the interrogator in a distance

$$d_{T,IA} > \frac{2L^2}{\lambda}, d_{T,MA} > \frac{2L^2}{\lambda}$$

with L being the maximum dimension of the interrogator antenna according to Figure 4.